

April 1991 Revised August 1999

74FR9244

9-Bit Buffer/Line Driver with 3-STATE Outputs

General Description

The 74FR9244 is a non-inverting 9-bit buffer and line driver designed to be employed as memory and address driver, clock driver and bus-oriented transmitter/receiver.

Features

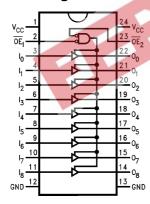
- 3-STATE outputs drive bus lines or buffer memory address registers
- Outputs sink 64 mA and source 15 mA
- Guaranteed multiple output switching, 250 pf delays and pin-to-pin skew
- Guaranteed 4000V minimum ESD protection
- 9-Bit architecture for systems carrying parity

Ordering Code:

Order Number	Package Number	Package Description
74FR9244SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74FR9244SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagram



Pin Descriptions

`	Pin Names	Description				
	$\overline{OE}_1, -\overline{OE}_2$	Output Enable Input (Active-LOW)				
	I ₀ –I ₈	Inputs				
	O ₀ –O ₈	Outputs				

Truth Table

ŌE ₁	OE ₂	l _n	O _n
Н	Х	Х	Z
Х	Н	Х	Z
L	L	Н	Н
L	L	L	L

H = HIGH Voltage Level L = LOW Voltage Level

X = Immaterial Z = High Impedance

Absolute Maximum Ratings(Note 1)

Recommended Operating Conditions

-65°C to +150°C Storage Temperature

Ambient Temperature Under Bias -55°C to +125°C Junction Temperature Under Bias -55°C to +150°C V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0V Input Current (Note 2) $-30\ \text{mA}$ to $+5.0\ \text{mA}$

Voltage Applied to Output in HIGH State (with V_{CC} = 0V)

Standard Output 3-STATE Output -0.5V to +5.5V

Current Applied to Output

Twice The Rated I_{OL} (mA) in LOW State (Max) ESD Last Passing Voltage (Min)

Free Air Ambient Temperature +4.5V to +5.5V Supply Voltage

 0°C to $+70^{\circ}\text{C}$

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

De Liectrical Characteristics							
Symbol	Parameter	Min	Тур	Max	Units	Vcc	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V _{IL}	Input LOW Voltage			0.8	V	C	Recognized LOW Signal
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = −18 mA
V _{OH}	Output HIGH Voltage	2.4		137	V	Min	I _{OH} = -3 mA
		2.0		-	V	Min	I _{OH} = -15 mA
V _{OL}	Output LOW Voltage			0.55	V	Min	I _{OL} = 64 mA
I _{IH}	Input HIGH Current			5	μА	Max	V _{IN} = 2.7V
I _{BVI}	Input HIGH Current Breakdown Test)		7	μΑ	Max	V _{IN} = 7.0V
I _{IL}	Input LOW Current			-150	μΑ	Max	V _{IN} = 0.5V
V _{ID}	Input Leakage Test	4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A},$
							All Other Pins Grounded
l _{OD}	Output Circuit Leakage Current			3.75	μΑ	0.0	V _{IOD} = 150 mV,
							All Other Pins Grounded
l _{OZH}	Output Leakage Current			20	μΑ	Max	V _{OUT} = 2.7V
I _{OZL}	Output Leakage Current			-20	μΑ	Max	V _{OUT} = 0.5V
los	Output Short-Circuit Current	-100		-225	mA	Max	V _{OUT} = 0.0V
I _{CEX}	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC}$
I _{ZZ}	Bus Drainage Test			100	μΑ	0.0	V _{OUT} = 5.25V
Іссн	Power Supply Current		30	40	mA	Max	All Outputs HIGH
I _{CCL}	Power Supply Current		60	75	mA	Max	All Outputs LOW
I _{CCZ}	Power Supply Current		35	45	mA	Max	Outputs 3-STATED
C _{IN}	Input Capacitance		8.0		pF	5.0	

AC Electrical Characteristics

Symbol	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$			$T_A = 0$ °C to $+70$ °C $V_{CC} = +5.0$ V $C_L = 50$ pF		Units
		Min	Тур	Max	Min	Max	
t _{PLH}	Propagation Delay	1.0	2.6	4.1	1.0	4.1	ns
t _{PHL}		1.0	1.8	4.1	1.0	4.1	115
t _{PZH}	Output Enable Time	2.6	4.8	7.0	2.6	7.0	ns
t_{PZL}		2.6	3.9	7.0	2.6	7.0	115
t _{PHZ}	Output Disable Time	1.6	3.7	6.1	1.6	6.1	ns
t_{PLZ}		1.6	3.6	6.1	1.6	6.1	115

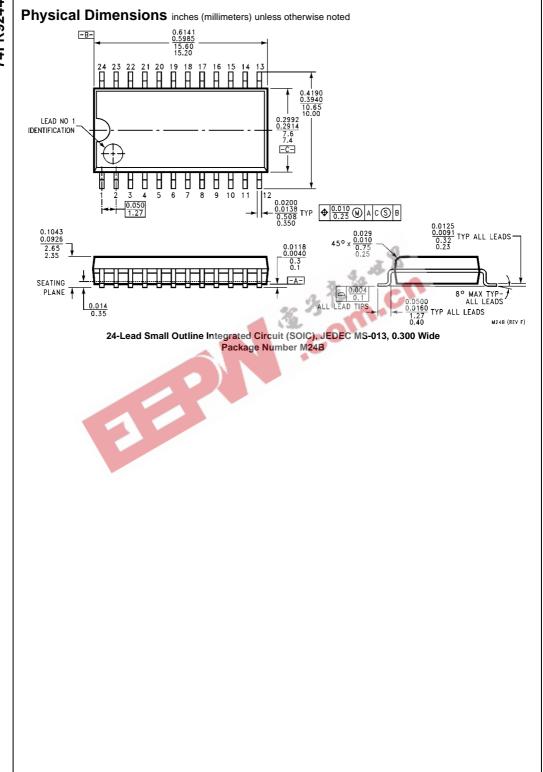
Extended AC Characteristics

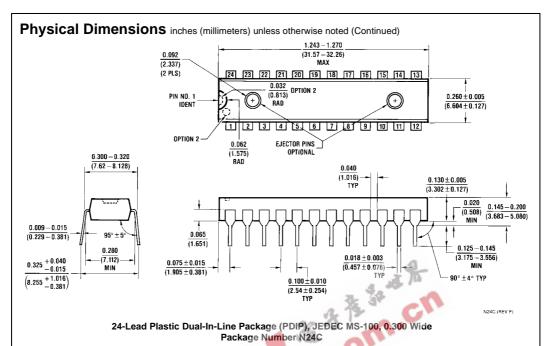
Symbol	Parameter	$T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$ Eight Outputs Switching (Note 3)		表版		Units
+	Propagation Delay	Min 1.0	Max 6.0	Min	Max 8.0	
t _{PLH} t _{PHL}	Propagation Delay	1.0	6.0	2.3	8.0	ns
t _{PZH}	Output Enable Time	2.6 2.6	8. 5 8 .5			ns
t _{PHZ}	Output Disable Time	1.6 1.6	6.5 6.5			ns
t _{OSHL}	Pin-to-Pin Skew for HL Transitions (Note 5)		1.3			ns
t _{OSLH}	Pin-to-Pin Skew for LH Transitions (Note 5)		1.7			ns
t _{OST}	Pin-to-Pin Skew for HL/LH Transitions (Note 5)		3.0			ns

Note 3: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase, i.e., all LOW-to-HIGH, HIGH-to-LOW, 3-STATE-to-HIGH, etc.

Note 4: These specifications guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 5: Skew is defined as the absolute value of the difference between the actual propagation delays for any two outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW, (t_{OSHL}), LOW-to-HIGH, (t_{OSLH}), or HIGH-to-LOW and/or LOW-to-HIGH, (t_{OST}). Specification guaranteed with all outputs switching in phase.





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